

650V Super-Junction Power MOSFET

DESCRIPTION

650V super-junction Power MOSFET

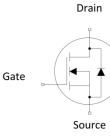
Super-junction power MOSFET is a revolutionary technology for high voltage power MOSFETs, designed according to the SJ principle. The SJ MOSFET is a price-performance optimized product enabling to target cost sensitive applications in Consumer and Lighting markets, designed by Wuxi Unigroup Microelectronics Company.

APPLICATIONS

FEATURES

- Ultra-fast body diode
- Very low FOM R_{DS(on)}×Q_q
- 100% avalanche tested
- RoHS compliant







Switch Mode Power Supply (SMPS)

Uninterruptible Power Supply (UPS)

Power Factor Correction (PFC)

Device Marking and Package InformationDevicePackageMarkingTPW65R190MFDTO-24765R190MFD

Key Performance Parameters				
Parameter	Value	Unit		
V _{DS} @ T _{j,max}	650	V		
R _{DS(on),max}	0.19	Ω		
I _D	20	А		
Q _{g,typ}	42	nC		
I _{DM}	60	А		
t _{rr}	112	ns		
Q _{rr}	0.54	μC		
I _{rrm}	9.6	A		

Absolute Maximum Ratings $T_c = 25^{\circ}C$, unless otherwise noted					
Parameter		Symbol	Value	Unit	
Drain-Source Voltage (V _{GS} = 0V)		V _{DSS}	650	V	
Continuous Drain Current	T _C = 25°C		20		
Continuous Drain Current	TC = 100°C	I _D	12		
Pulsed Drain Current	(note1)	I _{DM}	60	А	
Gate-Source Voltage		V _{GSS}	±30	V	
Single Pulse Avalanche Energy	(note2)	E _{AS}	484	mJ	
Repetitive Avalanche Energy (note2)		E _{AR}	0.7	mJ	
Avalanche Current		I _{AR}	3.5	A	
MOSFET dv/dt ruggedness, V _{DS} = 0480V		dv/dt	50	V/ns	
Power Dissipation		P _D	151	w	
Continuous Body Diode Current		۱ _s	17		
Pulsed Diode Forward Current (note1)		I _{SM}	60	A	
Reverse diode dv/dt (note3)		dv/dt	50	V/ns	
Maximum diode commutation speed (note3)		di _f /dt	900	A/us	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	-55~+150	°C	

Thermal Resistance				
Parameter	Symbol	Value	Unit	
Thermal Resistance, Junction-to-Case	R _{thJC}	0.83	00.00/	
Thermal Resistance, Junction-to-Ambient	R _{thJA}	62	⁰C/W	



Deremeter			Value				
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0V, I_{D} = 250\mu A$	650			V	
		$V_{DS} = 650V, V_{GS} = 0V, T_{J} = 25^{\circ}C$			5	μΑ	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 650V, V_{GS} = 0V, T_{J} = 150^{\circ}C$			2500		
Gate-Source Leakage	I _{GSS}	$V_{GS} = \pm 30 V$			±100	nA	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \mu A$	3		5	V	
Drain-Source On-Resistance	R _{DS(on)}	V _{GS} = 10V, I _D = 10A		0.17	0.19	Ω	
Gate resistance	R _G	f = 1.0MHz open drain		12		Ω	
Dynamic	-						
Input Capacitance	C _{iss}			1834		pF	
Output Capacitance	C _{oss}	$V_{GS} = 0V,$ $V_{DS} = 100V,$		57			
Reverse Transfer Capacitance	C _{rss}	f = 1.0MHz		1.7			
Total Gate Charge	Qg			42		nC	
Gate-Source Charge	Q _{gs}	$V_{DD} = 520V, I_{D} = 20A, V_{GS} = 10V$		10			
Gate-Drain Charge	Q _{gd}			17			
Turn-on Delay Time	t _{d(on)}			34			
Turn-on Rise Time	t _r	V _{DD} = 400V, I _D = 20A,		72			
Turn-off Delay Time	t _{d(off)}	$R_{\rm G} = 25\Omega$		114		ns	
Turn-off Fall Time	t _f			41			
Drain-Source Body Diode Characte	eristics	· · · · · · · · · · · · · · · · · · ·		-			
Body Diode Voltage	V _{SD}	$T_J = 25^{o}C, I_{SD} = 10A, V_{GS} = 0V$		1.0	1.5	V	
Reverse Recovery Time	t _{rr}			112		ns	
Reverse Recovery Charge	Q _{rr}	$V_R = 400V, I_F = I_S,$ $di_F/dt = 100A/\mu s$		0.54		μC	
Peak Reverse Recovery Current	I _{rrm}			9.6		А	

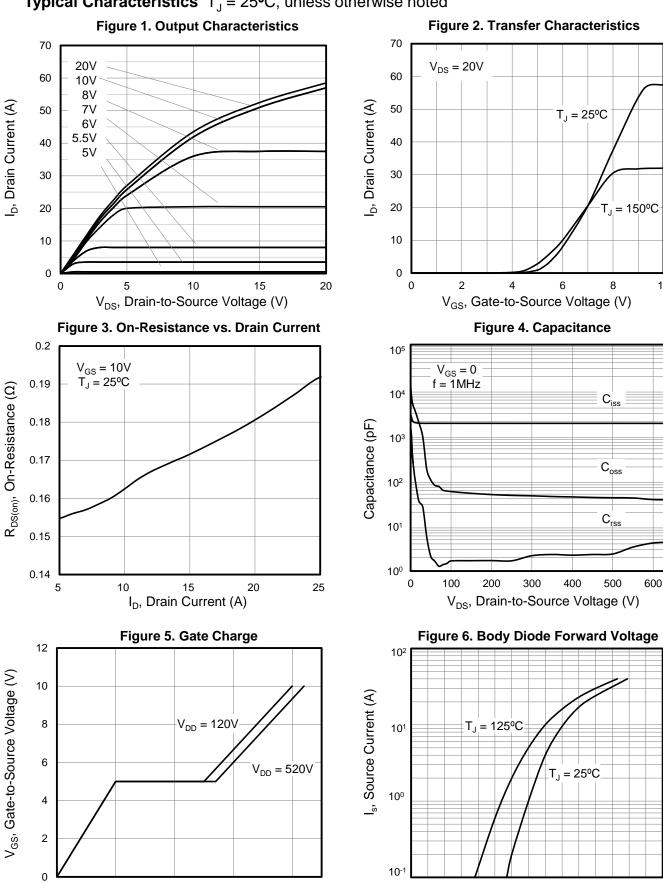
Notes

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. I_{AS} = 3.5A, V_{DD} = 50V, R_{G} = 25 Ω , Starting T_{J} = 25°C
- 3. Identical low side and high side switch with identical ${\sf R}_{\sf G}$



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Typical Characteristics $T_J = 25^{\circ}C$, unless otherwise noted

0

20

Q_g, Total Gate Charge (nC)

10

30

40

1.5

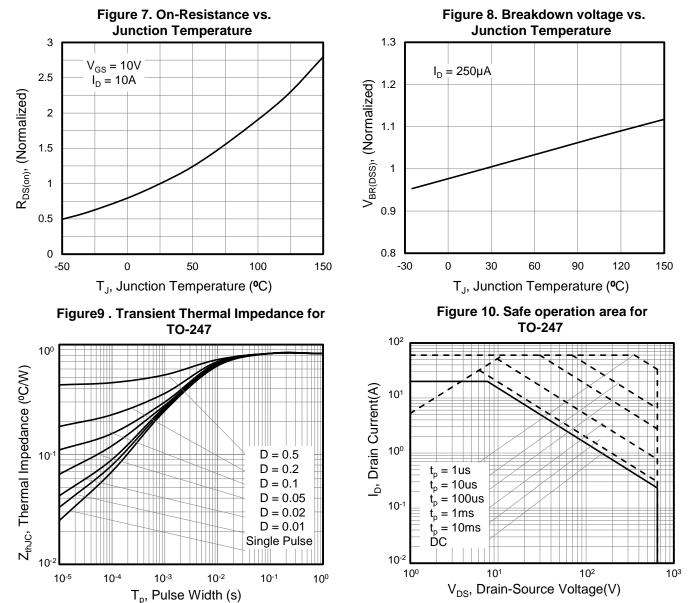
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0.5

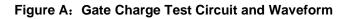
V_{SD}, Source-to-Drain Voltage (V)

0





Typical Characteristics $T_J = 25^{\circ}C$, unless otherwise noted



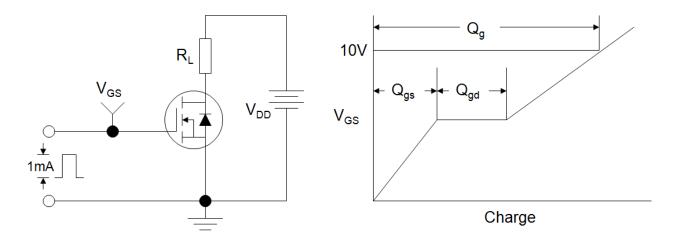


Figure B: Resistive Switching Test Circuit and Waveform

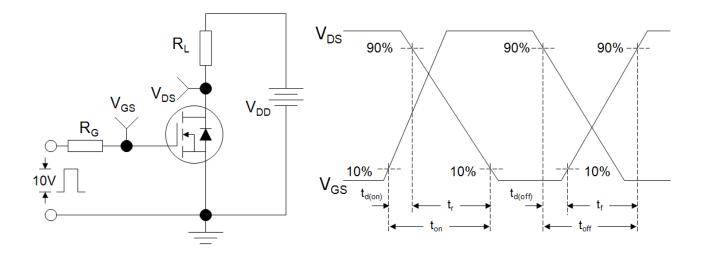
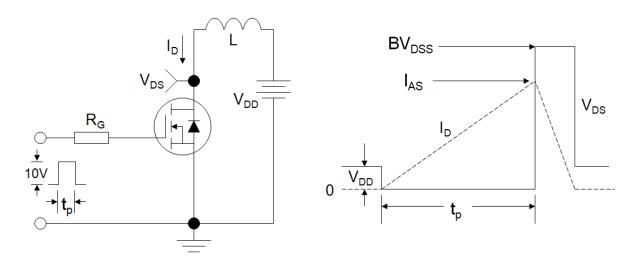


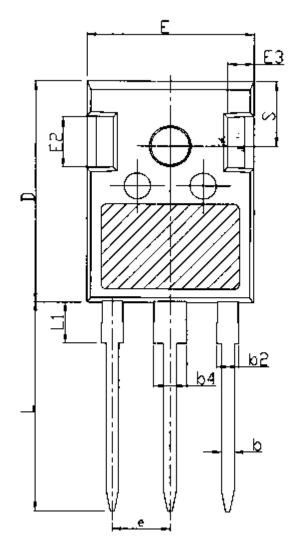
Figure C: Unclamped Inductive Switching Test Circuit and Waveform

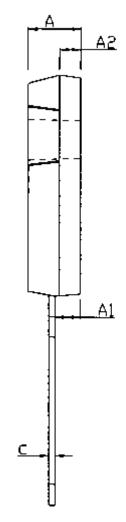


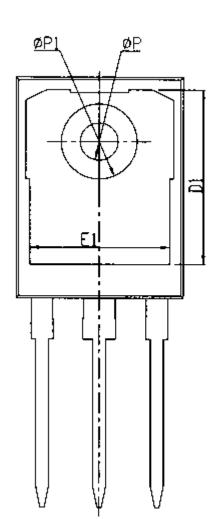
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TO-247







Unit:mm					
Symbol	Min.	Nom	Max.		
А	4.80	5.00	5.20		
A1	2.21	2.41	2.61		
A2	1.85	2.00	2.15		
b	1.11	1.21	1.36		
b2	1.91	2.01	2.21		
b4	2.91	3.01	3.21		
С	0.51	0.61	0.75		
D	20.70	21.00	21.30		
D1	16.25	16.55	16.85		

Unit:mm				
Symbol	Min. Nom. Max.			
E	15.50	15.80	16.10	
E1	13.00	13.30	13.60	
E2	4.80	5.00	5.20	
E3	2.30	2.50	2.70	
е	5.44BSC			
L	19.62	19.92	20.22	
L1	-	-	4.30	
ΦΡ	3.40	3.60	3.80	
ΦP1	-	-	7.30	
S	6.15BSC			



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